











THVD1419, THVD1429

SLLSF32C - NOVEMBER 2018 - REVISED MARCH 2019

## THVD14x9 3.3-V to 5-V RS-485 transceivers with surge protection

#### **Features**

- Meets or Exceeds the Requirements of the TIA/EIA-485A Standard
- 3 V to 5.5 V Supply Voltage
- **Bus I/O Protection** 
  - ± 16 kV HBM ESD
  - ± 8 kV IEC 61000-4-2 Contact Discharge
  - ± 30 kV IEC 61000-4-2 Air-Gap Discharge
  - ± 4 kV IEC 61000-4-4 Electrical Fast Transient
  - ± 2.5 kV IEC 61000-4-5 1.2/50-μs Surge
- Available in Two Speed Grades
  - THVD1419: 250 kbps
  - THVD1429: 20 Mbps
- **Extended Ambient**

Temperature Range: -40°C to 125°C

- **Extended Operational** 
  - Common-Mode Range: ± 12 V
- Receiver Hysteresis for Noise Rejection: 30 mV
- Low Power Consumption
  - Standby Supply Current: < 2 μA</li>
  - Current During Operation: < 3 mA</li>
- Glitch-Free Power-Up/Down for Hot Plug-in Capability
- Open, Short, and Idle Bus Failsafe
- 1/8 Unit Load (Up to 256 Bus Nodes)
- Industry Standard 8-Pin SOIC for Drop-in Compatibility

### **Applications**

- Wireless Infrastructure
- **Building Automation**
- **HVAC Systems**
- **Factory Automation & Control**
- **Grid Infrastructure**
- **Smart Meters**
- **Process Analytics**
- Video Surveillance

### 3 Description

THVD1419 and THVD1429 are half-duplex RS-485 transceivers with integrated surge protection. Surge protection is achieved by integrating transient voltage suppressor (TVS) diodes in the standard 8-pin SOIC (D) package. This feature provides a substantial increase in reliability for better immunity to noise transients coupled to the data cable, eliminating the need for external protection components.

Each of these devices operates from a single 3.3 V or 5 V supply. The devices in this family feature a wide common-mode voltage range which makes them suitable for multi-point applications over long cable

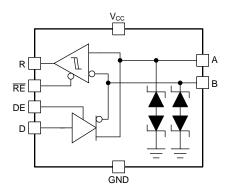
The THVD1419 and THVD1429 devices are available in the industry standard SOIC package for easy dropin without any PCB changes. These devices are characterized over ambient free-air temperatures from -40°C to 125°C.

#### Device Information<sup>(1)</sup>

PART NUMBER	PACKAGE	BODY SIZE (NOM)
THVD1419 THVD1429	SOIC (8)	4.90 mm × 3.91 mm

(1) For all available devices, see the orderable addendum at the end of the data sheet.

#### THVD1419 and THVD1429 Block Diagram



Page



## **Table of Contents**

1 Features	13
3 Description	16
4 Revision History	17
5 Device Comparison Table 3 10.2 Typical Application 10.2 Typical Appli	17
· 44 Dawar Cumply Dacammandations	17
6 Pin Configuration and Functions4	20
7 Specifications 5 12 Layout	21
7.1 Absolute Maximum Ratings	21
7.1 Absolute Maximum Ratings	
7.3 ESD Ratings [IEC]	22
7.4 Recommended Operating Conditions 6 13.1 Device Support	
7.5 Thermal Information	
7.6 Power Dissipation	
7.7 Electrical Characteristics	dates 22
7.8 Switching Characteristics 8 13.5 Community Resources	22
7.9 Typical Characteristics	22
8 Parameter Measurement Information	22
13.8 Clossany	22
9.1 Overview 13 Mechanical, Packaging, and Orderable	22
9.2 Functional Block Diagrams	22

## 4 Revision History

C	hanges from Revision B (December 2018) to Revision C	Page
•	Changed THVD1419 From: Product Preview To: Production data	1
•	Changed power dissipation numbers of THVD1419	6
•	Changed THVD1419 driver switching characteristics	8
•	Changed THVD1419 receiver switching characteristics	8
•	Added Figure 7 to Figure 9	9

# Changes from Revision A (December 2018) to Revision B



## 5 Device Comparison Table

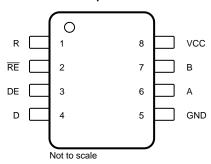
PART NUMBER	DUPLEX	ENABLES	ENABLES SIGNALING RATE			
THVD1419	Llolf	DE. RE	up to 250 kbps	256		
THVD1429	Half	DE, RE	up to 20 Mbps	256		

Copyright © 2018–2019, Texas Instruments Incorporated



## 6 Pin Configuration and Functions

### THVD1419, THVD1429 Devices 8-Pin D Package (SOIC) Top View



#### **Pin Functions**

PIN		1/0	DECORIDATION		
NAME	NO.	- I/O	DESCRIPTION		
Α	6	Bus input/output	Bus I/O port, A (complementary to B)		
В	7	Bus input/output	Bus I/O port, B (complementary to A)		
D	4	Digital input	Driver data input		
DE	3	Digital input	Driver enable, active high (2-MΩ internal pull-down)		
GND	5	Ground	Device ground		
R	1	Digital output	Receive data output		
V <sub>CC</sub>	8	Power	3.3-V to 5-V supply		
RE	2	Digital input	Receiver enable, active low (2-MΩ internal pull-up)		



## 7 Specifications

#### 7.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1)

		MIN	MAX	UNIT
Supply voltage	V <sub>CC</sub>	-0.5	7	V
Bus voltage	Range at any bus pin (A or B) as differential or common-mode with respect to GND	-15	15	٧
Input voltage	Range at any logic pin (D, DE, or /RE)	-0.3	5.7	V
Receiver output current	Io	-24	24	mA
Storage temperature range		-65	150	°C

Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### 7.2 ESD Ratings

				VALUE	UNIT
		Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, 2010	Bus terminals and GND	±16	kV
V <sub>(ESD)</sub> Electrostatic discharge	Electrostatic discharge	c discharge	All other pins	±8	kV
	Charged device model (CDM), per JEDEC JESD22-C101E	All pins	±1.5	kV	

## 7.3 ESD Ratings [IEC]

				VALUE	UNIT
V <sub>(ESD)</sub>	Flootrootatio disaborga	Contact Discharge, per IEC 61000-4-2	Bus pins and GND	±8	kV
	Electrostatic discharge	Air-Gap Discharge, per IEC 61000-4-2	Bus pins and GND	±30	kV
V <sub>(EFT)</sub>	Electrical fast transient	Per IEC 61000-4-4	Bus pins and GND	±4	kV
V <sub>(surge)</sub>	Surge	Per IEC 61000-4-5, 1.2/50 μs	Bus pins and GND	±2.5	kV

Copyright © 2018-2019, Texas Instruments Incorporated



### 7.4 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)(1)

		MIN	NOM	MAX	UNIT
V <sub>CC</sub>	Supply voltage	3		5.5	V
VI	Input voltage at any bus terminal (separately or common mode) (1)	-12		12	V
V <sub>IH</sub>	High-level input voltage (driver, driver enable, and receiver enable inputs)	2		V <sub>CC</sub>	V
V <sub>IL</sub>	Low-level input voltage (driver, driver enable, and receiver enable inputs)	0		0.8	V
V <sub>ID</sub>	Differential input voltage	-12		12	V
l <sub>O</sub>	Output current, driver	-60		60	mA
lor	Output current, receiver	-8		8	mA
$R_L$	Differential load resistance	54			Ω
1/t <sub>UI</sub>	Signaling rate: THVD1419			250	kbps
1/t <sub>UI</sub>	Signaling rate: THVD1429			20	Mbps
ГА	Operating ambient temperature	-40		125	°C
TJ	Junction temperature	-40		150	°C

<sup>(1)</sup> The algebraic convention, in which the least positive (most negative) limit is designated as minimum is used in this data sheet.

#### 7.5 Thermal Information

		THVD14x9	
	THERMAL METRIC <sup>(1)</sup>	D (SOIC)	UNIT
		8-PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	120.7	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	50.3	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	62.8	°C/W
$\Psi_{JT}$	Junction-to-top characterization parameter	7.5	°C/W
$\Psi_{JB}$	Junction-to-board characterization parameter	62.2	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	N/A	°C/W

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report, SPRA953.

### 7.6 Power Dissipation

PARAMETER	Description	TEST CONDITIONS	VALUE	UNIT
	Driver and receiver enabled, V <sub>CC</sub> = 5.5 V, T <sub>A</sub>	Unterminated: $R_L = 300 \Omega$ , $C_L = 50 pF$	230	mW
	= 125 °C, 50% duty cycle square wave at maximum signaling rate, THVD1419  Driver and receiver enabled, V <sub>CC</sub> = 5.5 V, T <sub>A</sub> = 125 °C, 50% duty cycle square wave at	RS-422 load: $R_L = 100 \Omega$ , $C_L = 50 pF$	350	mW
D		RS-485 load: $R_L = 54 \Omega$ , $C_L = 50 pF$	470	mW
P <sub>D</sub>		Unterminated: $R_L = 300 \Omega$ , $C_L = 50 pF$	350	mW
		RS-422 load: $R_L = 100 \Omega$ , $C_L = 50 pF$	290	mW
	maximum signaling rate, THVD1429	RS-485 load: $R_L$ = 54 $\Omega$ , $C_L$ = 50 pF	300	mW



#### 7.7 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
Driver							
V <sub>OD</sub>	Driver differential output voltage magnitude	$R_L = 60 Ω$ , -12 V ≤ $V_{test} ≤ 12 V$ , se	e Figure 10	1.5	3.5		V
V <sub>OD</sub>	Driver differential output voltage magnitude	$R_L = 60 \Omega$ , -12 V ≤ V <sub>test</sub> ≤ 12 V, 4.5 5.5 V, see Figure 10	5 V ≤ V <sub>CC</sub> ≤	2.1			V
V <sub>OD</sub>	Driver differential output voltage magnitude	$R_L = 100 \Omega$ , see Figure 11		2	4		V
V <sub>OD</sub>	Driver differential output voltage magnitude	$R_L = 54 \Omega$ , see Figure 11		1.5	3.5		V
Δ V <sub>OD</sub>	Change in differential output voltage			-200		200	mV
V <sub>oc</sub>	Common-mode output voltage	$R_L = 54 \Omega$ , see Figure 11		1	V <sub>CC</sub> /	3	V
$\Delta V_{OC(SS)}$	Change in steady-state common- mode output voltage			-200		200	mV
Ios	Short-circuit output current	$DE = V_{CC}$ , -7 $V \le V_O \le 12 V$		-250	-	250	mA
Receiver							
			V <sub>I</sub> = 12 V		50	125	μΑ
I <sub>I</sub>	Bus input current	DE = 0 V, V <sub>CC</sub> = 0 V or 5.5 V	V <sub>I</sub> = -7 V	-100	-65		μA
		V <sub>I</sub> = -12 V		-150	-100		μA
V <sub>TH+</sub>	Positive-going input threshold voltage	Over common-mode range of ±12 V		See <sup>(1)</sup>	-100	-20	mV
V <sub>TH-</sub>	Negative-going input threshold voltage			-200	-130	See <sup>(1)</sup>	mV
V <sub>HYS</sub>	Input hysteresis				30		mV
C <sub>A,B</sub>	Input differential capacitance	Measured between A and B, f = 1	MHz		220		pF
V <sub>OH</sub>	Output high voltage	I <sub>OH</sub> = -8 mA		V <sub>CC</sub> - 0.4	V <sub>CC</sub> – 0.3		V
V <sub>OL</sub>	Output low voltage	I <sub>OL</sub> = 8 mA			0.2	0.4	V
I <sub>OZR</sub>	Output high-impedance current	$V_O = 0 \text{ V or } V_{CC}, \overline{RE} = V_{CC}$		-1		1	μA
Logic							
I <sub>IN</sub>	Input current (D, DE, RE)	4.5 V ≤ V <sub>CC</sub> ≤ 5.5 V		-6.2		6.2	μA
Device				l .			
		Driver and receiver enabled	$\overline{RE} = 0 \text{ V},$ $DE = V_{CC},$ No load		2.4	3	mA
		Driver enabled, receiver disabled	$\overline{RE} = V_{CC},$ $DE = V_{CC},$ No load		2	2.6	mA
I <sub>CC</sub>	Supply current (quiescent)	Driver disabled, receiver enabled	RE = 0 V, DE = 0V, No load		700	960	μΑ
		Driver and receiver disabled	RE = V <sub>CC</sub> , DE = 0 V, D = open, No load		0.1	2	μА
T <sub>SD</sub>	Thermal shutdown temperature		•		170		°C

<sup>(1)</sup> Under any specific conditions,  $V_{TH+}$  is assured to be at least  $V_{HYS}$  higher than  $V_{TH-}$ .



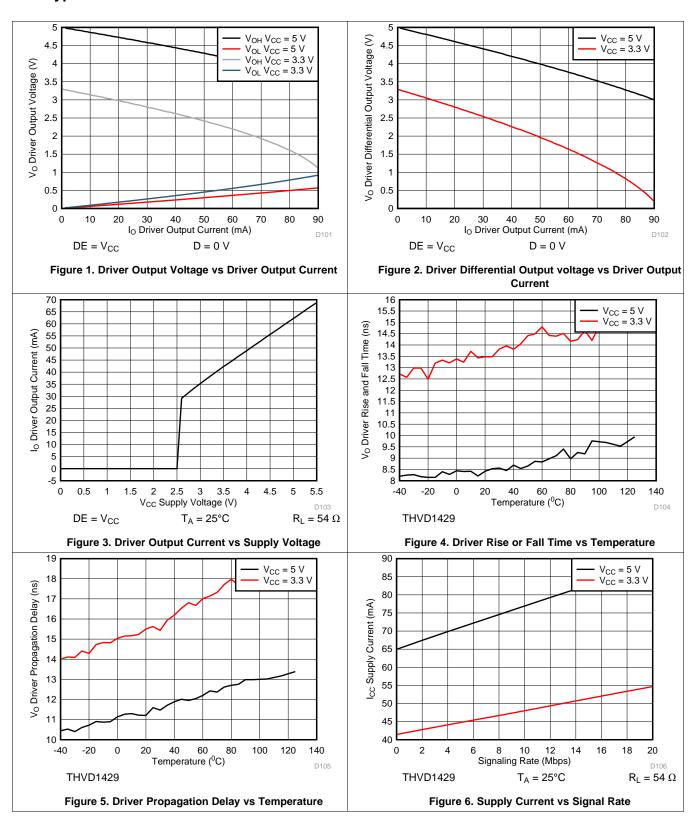
## 7.8 Switching Characteristics

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
Driver: THVD	1419					
t <sub>r</sub> , t <sub>f</sub>	Differential output rise / fall time			300	500	ns
t <sub>PHL</sub> , t <sub>PLH</sub>	Propagation delay	$R_L = 54 \Omega$ , $C_L = 50 pF$ , see Figure 12		200	450	ns
t <sub>SK(P)</sub>	Pulse skew,  t <sub>PHL</sub> - t <sub>PLH</sub>				40	ns
t <sub>PHZ</sub> , t <sub>PLZ</sub>	Disable time			20	50	ns
t t	Enable time	RE = 0 V, see Figure 13 and Figure 14		60	250	ns
t <sub>PZH</sub> , t <sub>PZL</sub>	Lilable time	RE = V <sub>CC</sub> , see Figure 13 and Figure 14		3	11	μs
Receiver: TH	VD1419					
t <sub>r</sub> , t <sub>f</sub>	Output rise / fall time			14	20	ns
t <sub>PHL</sub> , t <sub>PLH</sub>	Propagation delay	C <sub>L</sub> = 15 pF, see Figure 15		30	50	ns
t <sub>SK(P)</sub>	Pulse skew,  t <sub>PHL</sub> - t <sub>PLH</sub>				7	ns
t <sub>PHZ</sub> , t <sub>PLZ</sub>	Disable time			35	45	ns
t <sub>PZH(1)</sub> , t <sub>PZL(1),</sub>		DE = V <sub>CC</sub> , see Figure 16		80	120	ns
$t_{PZH(2)}$ , $t_{PZL(2)}$ ,	Enable time	DE = 0 V, see Figure 17		5	14	μs
Driver: THVD	1429					
t <sub>r</sub> , t <sub>f</sub>	Differential output rise / fall time			9	16	ns
t <sub>PHL</sub> , t <sub>PLH</sub>	Propagation delay	$R_L = 54 \Omega$ , $C_L = 50 pF$ , see Figure 12		12	25	ns
t <sub>SK(P)</sub>	Pulse skew,  t <sub>PHL</sub> - t <sub>PLH</sub>				6	ns
t <sub>PHZ</sub> , t <sub>PLZ</sub>	Disable time			18	40	ns
<b>+ +</b>	Enable time	RE = 0 V, see Figure 13 and Figure 14		16	40	ns
t <sub>PZH</sub> , t <sub>PZL</sub>	Lilable time	RE = V <sub>CC</sub> , see Figure 13 and Figure 14		2.8	11	μs
Receiver: TH	VD1429					
t <sub>r</sub> , t <sub>f</sub>	Output rise / fall time			2	6	ns
t <sub>PHL</sub> , t <sub>PLH</sub>	Propagation delay	C <sub>L</sub> = 15 pF, see Figure 15		12	45	ns
t <sub>SK(P)</sub>	Pulse skew,  t <sub>PHL</sub> - t <sub>PLH</sub>				6	ns
t <sub>PHZ</sub> , t <sub>PLZ</sub>	Disable time			14	28	ns
t <sub>PZH(1)</sub> , t <sub>PZL(1)</sub> , t <sub>PZH(2)</sub> ,	Enable time	DE = V <sub>CC</sub> , see Figure 16		75	110	ns
$t_{PZL(2)}$ ,		DE = 0 V, see Figure 17		4.8	14	μs

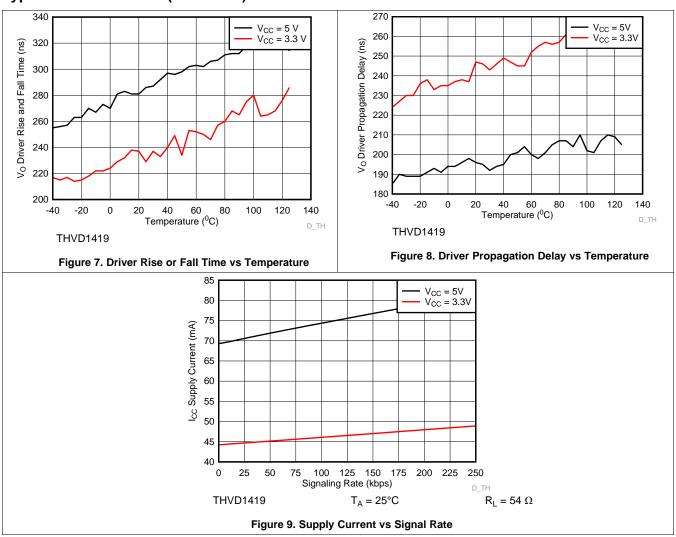


#### 7.9 Typical Characteristics





#### **Typical Characteristics (continued)**





#### 8 Parameter Measurement Information

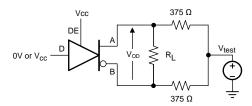


Figure 10. Measurement of Driver Differential Output Voltage With Common-Mode Load



Figure 11. Measurement of Driver Differential and Common-Mode Output With RS-485 Load

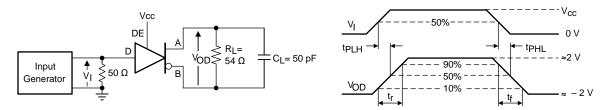


Figure 12. Measurement of Driver Differential Output Rise and Fall Times and Propagation Delays

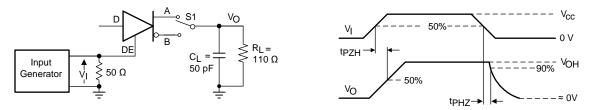


Figure 13. Measurement of Driver Enable and Disable Times With Active High Output and Pull-Down Load

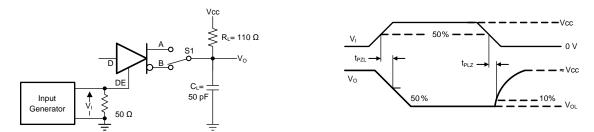


Figure 14. Measurement of Driver Enable and Disable Times With Active Low Output and Pull-up Load

Copyright © 2018–2019, Texas Instruments Incorporated



## **Parameter Measurement Information (continued)**

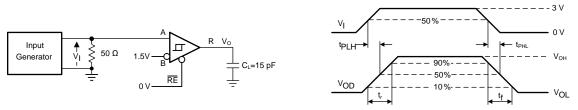


Figure 15. Measurement of Receiver Output Rise and Fall Times and Propagation Delays

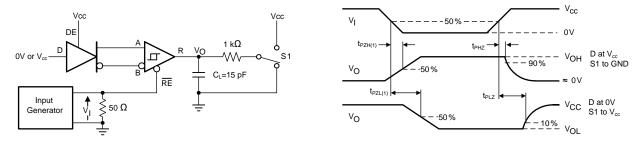


Figure 16. Measurement of Receiver Enable/Disable Times With Driver Enabled

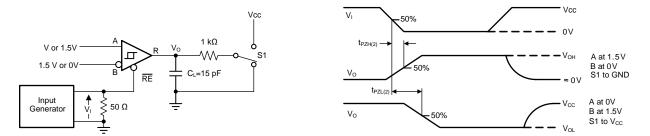


Figure 17. Measurement of Receiver Enable Times With Driver Disabled



## 9 Detailed Description

#### 9.1 Overview

THVD1419 and THVD1429 are surge-protected, half duplex RS-485 transceivers available in two speed grades suitable for data transmission up to 250 kbps and 20 Mbps respectively. Surge protection is achieved by integrating transient voltage suppresser (TVS) diodes in the standard 8-pin SOIC (D) package.

These devices have active-high driver enables and active-low receiver enables. A standby current of less than 2 µA can be achieved by disabling both driver and receiver.

### 9.2 Functional Block Diagrams

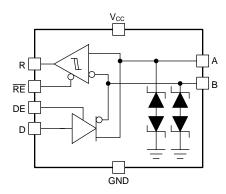


Figure 18. THVD1419 and THVD1429 Block Diagram

### 9.3 Feature Description

#### 9.3.1 Electrostatic Discharge (ESD) Protection

The bus pins of the THVD14x9 transceiver family include on-chip ESD protection against  $\pm 16$ -kV HBM and  $\pm 8$ -kV IEC 61000-4-2 contact discharge. The International Electrotechnical Commission (IEC) ESD test is far more severe than the HBM ESD test. The 50% higher charge capacitance,  $C_{(S)}$ , and 78% lower discharge resistance,  $R_{(D)}$ , of the IEC model produce significantly higher discharge currents than the HBM model. As stated in the IEC 61000-4-2 standard, contact discharge is the preferred transient protection test method.

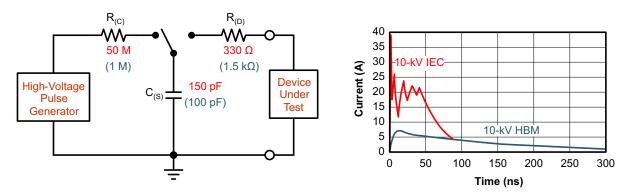


Figure 19. HBM and IEC ESD Models and Currents in Comparison (HBM Values in Parenthesis)

The on-chip implementation of IEC ESD protection significantly increases the robustness of equipment. Common discharge events occur because of human contact with connectors and cables.

Copyright © 2018–2019, Texas Instruments Incorporated



#### **Feature Description (continued)**

#### 9.3.2 Electrical Fast Transient (EFT) Protection

Inductive loads such as relays, switch contactors, or heavy-duty motors can create high-frequency bursts during transition. The IEC 61000-4-4 test is intended to simulate the transients created by such switching of inductive loads on AC power lines. Figure 20 shows the voltage waveforms in to  $50-\Omega$  termination as defined by the IEC standard.

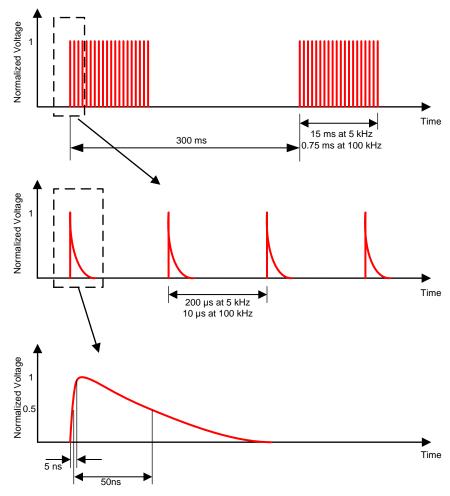


Figure 20. EFT Voltage Waveforms

Internal ESD protection circuits of the THVD14x9 protect the transceivers against EFT ±4 kV.

#### 9.3.3 Surge Protection

Surge transients often result from lightning strikes (direct strike or an indirect strike which induce voltages and currents), or the switching of power systems, including load changes and short circuit switching. These transients are often encountered in industrial environments, such as factory automation and power-grid systems.

Figure 21 compares the pulse-power of the EFT and surge transients with the power caused by an IEC ESD transient. The left hand diagram shows the relative pulse-power for a 0.5-kV surge transient and 4-kV EFT transient, both of which dwarf the 10-kV ESD transient visible in the lower-left corner. 500-V surge transients are representative of events that may occur in factory environments in industrial and process automation.

The right hand diagram shows the pulse-power of a 6-kV surge transient, relative to the same 0.5-kV surge transient. 6-kV surge transients are most likely to occur in power generation and power-grid systems.



### **Feature Description (continued)**

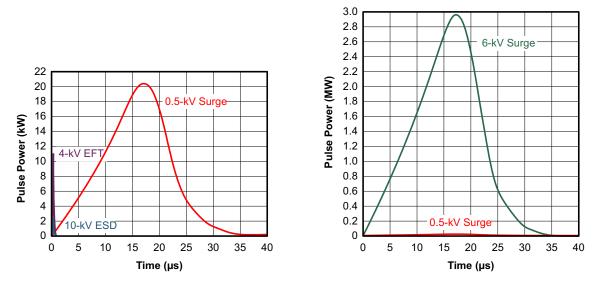


Figure 21. Power Comparison of ESD, EFT, and Surge Transients

Figure 22 shows the test setup used to validate THVD14x9 surge performance according to the IEC 61000-4-5 1.2/50-μs surge pulse.

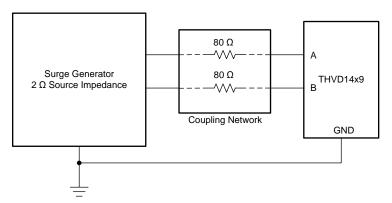


Figure 22. THVD14x9 Surge Test Setup

THVD14x9 product family is robust to ±2.5-kV surge transients without the need for any external components.

#### 9.3.4 Failsafe Receiver

The differential receivers of the THVD14x9 family are failsafe to invalid bus states caused by the following:

- · Open bus conditions, such as a disconnected connector
- · Shorted bus conditions, such as cable damage shorting the twisted-pair together
- Idle bus conditions that occur when no driver on the bus is actively driving

In any of these cases, the differential receiver will output a failsafe logic high state so that the output of the receiver is not indeterminate.

Copyright © 2018–2019, Texas Instruments Incorporated



#### 9.4 Device Functional Modes

When the driver enable pin, DE, is logic high, the differential outputs A and B follow the logic states at data input D. A logic high at D causes A to turn high and B to turn low. In this case the differential output voltage defined as  $V_{OD} = V_A - V_B$  is positive. When D is low, the output states reverse: B turns high, A becomes low, and  $V_{OD}$  is negative.

When DE is low, both outputs turn high-impedance. In this condition the logic state at D is irrelevant. The DE pin has an internal pull-down resistor to ground, thus when left open the driver is disabled (high-impedance) by default. The D pin has an internal pull-up resistor to  $V_{CC}$ , thus, when left open while the driver is enabled, output A turns high and B turns low.

**Table 1. Driver Function Table** 

INPUT	ENABLE	OUTI	PUTS	FUNCTION			
D	DE	Α	В	FONCTION			
Н	Н	Н	L	Actively drive bus high			
L	Н	L H		Actively drive bus low			
Х	L	Z	Z	Driver disabled			
Х	OPEN	Z	Z	Driver disabled by default			
OPEN	Н	H L		Actively drive bus high by default			

When the receiver enable pin,  $\overline{RE}$ , is logic low, the receiver is enabled. When the differential input voltage defined as  $V_{ID} = V_A - V_B$  is higher than the positive input threshold,  $V_{TH+}$ , the receiver output, R, turns low. If  $V_{ID}$  is between  $V_{TH+}$  and  $V_{TH-}$  the output is indeterminate.

When  $\overline{RE}$  is logic high or left open, the receiver output is high-impedance and the magnitude and polarity of  $V_{ID}$  are irrelevant. Internal biasing of the receiver inputs causes the output to go failsafe-high when the transceiver is disconnected from the bus (open-circuit), the bus lines are shorted to one another (short-circuit), or the bus is not actively driven (idle bus).

**Table 2. Receiver Function Table** 

DIFFERENTIAL INPUT	ENABLE	OUTPUT	FUNCTION
$V_{ID} = V_A - V_B$	RE	R	FUNCTION
$V_{TH+} < V_{ID}$	L	Н	Receive valid bus high
$V_{TH-} < V_{ID} < V_{TH+}$	L	?	Indeterminate bus state
$V_{ID} < V_{TH-}$	L	L	Receive valid bus low
X	Н	Z	Receiver disabled
X	OPEN	Z	Receiver disabled by default
Open-circuit bus	L	Н	Fail-safe high output
Short-circuit bus	L	Н	Fail-safe high output
Idle (terminated) bus	L	Н	Fail-safe high output



## 10 Application and Implementation

#### NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

#### 10.1 Application Information

THVD14x9 are half-duplex RS-485 transceivers with integrated system-level surge protection. Standard 8-pin SOIC (D) package allows drop-in replacement into existing systems and eliminate system-level protection components.

#### 10.2 Typical Application

An RS-485 bus consists of multiple transceivers connecting in parallel to a bus cable. To eliminate line reflections, each cable end is terminated with a termination resistor,  $R_T$ , whose value matches the characteristic impedance,  $Z_0$ , of the cable. This method, known as parallel termination, allows for higher data rates over longer cable length.

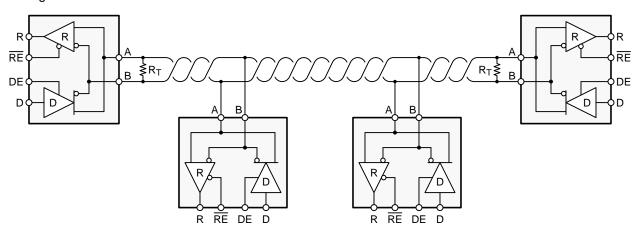


Figure 23. Typical RS-485 Network With Half-Duplex Transceivers

#### 10.2.1 Design Requirements

RS-485 is a robust electrical standard suitable for long-distance networking that may be used in a wide range of applications with varying requirements, such as distance, data rate, and number of nodes.

#### 10.2.1.1 Data Rate and Bus Length

There is an inverse relationship between data rate and cable length, which means the higher the data rate, the short the cable length; and conversely, the lower the data rate, the longer the cable length. While most RS-485 systems use data rates between 10 kbps and 100 kbps, some applications require data rates up to 250 kbps at distances of 4000 feet and longer. Longer distances are possible by allowing for small signal jitter of up to 5 or 10%.

(1)



### **Typical Application (continued)**

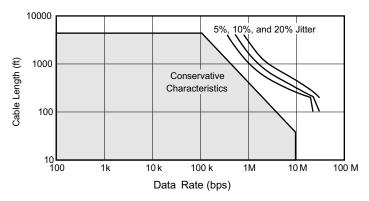


Figure 24. Cable Length vs Data Rate Characteristic

Even higher data rates are achievable (that is, 20 Mbps for the THVD1429) in cases where the interconnect is short enough (or has suitably low attenuation at signal frequencies) to not degrade the data.

#### 10.2.1.2 Stub Length

When connecting a node to the bus, the distance between the transceiver inputs and the cable trunk, known as the stub, should be as short as possible. Stubs present a non-terminated piece of bus line which can introduce reflections as the length of the stub increases. As a general guideline, the electrical length, or round-trip delay, of a stub should be less than one-tenth of the rise time of the driver, thus giving a maximum physical stub length as shown in Equation 1.

 $L_{(STUB)} \le 0.1 \times t_r \times v \times c$ 

#### where

- t<sub>r</sub> is the 10/90 rise time of the driver
- c is the speed of light  $(3 \times 10^8 \text{ m/s})$
- v is the signal velocity of the cable or trace as a factor of c

#### 10.2.1.3 Bus Loading

The RS-485 standard specifies that a compliant driver must be able to driver 32 unit loads (UL), where 1 unit load represents a load impedance of approximately 12 k $\Omega$ . Because the THVD14x9 devices consist of 1/8 UL transceivers, connecting up to 256 receivers to the bus is possible.



## **Typical Application (continued)**

#### 10.2.2 Detailed Design Procedure

RS-485 transceivers operate in noisy industrial environments typically require surge protection at the bus pins. Figure 25 compares 1-kV surge protection implementation with a regular RS-485 transceiver (such as THVD14x0) against with the THVD14x9. The internal TVS protection of the THVD14x9 achieves ±2.5 kV IEC 61000-4-5 surge protection without any additional external components, reducing system level bill of materials.

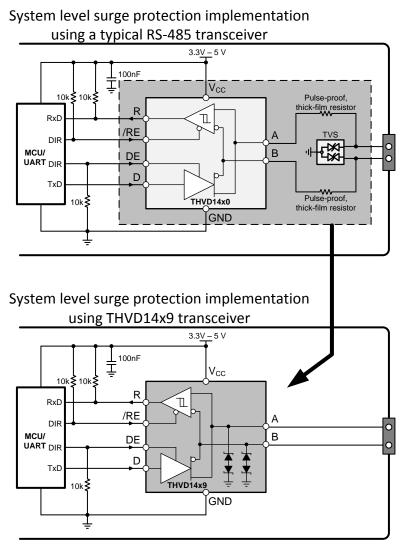
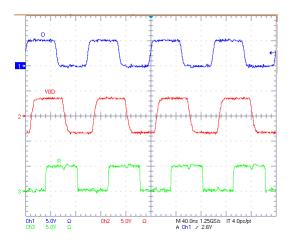


Figure 25. Implementation of System-Level Surge Protection Using THVD14x9



### **Typical Application (continued)**

#### 10.2.3 Application Curves



 $V_{CC} = 5 \text{ V}$  54- $\Omega$  Termination

 $T_A = 25^{\circ}C$ 

Figure 26. THVD1429 Waveforms at 20 Mbps

## 11 Power Supply Recommendations

To ensure reliable operation at all data rates and supply voltages, each supply should be decoupled with a 100-nF ceramic capacitor located as close to the supply pins as possible. This helps to reduce supply voltage ripple present on the outputs of switched-mode power supplies and also helps to compensate for the resistance and inductance of the PCB power planes.



## 12 Layout

### 12.1 Layout Guidelines

Additional external protection components generally are not needed when using THVD14x9 transceivers.

- 1. Use  $V_{CC}$  and ground planes to provide low-inductance. Note that high-frequency currents tend to follow the path of least impedance and not the path of least resistance. Apply 100-nF to 220-nF decoupling capacitors as close as possible to the  $V_{CC}$  pins of transceiver, UART and/or controller ICs on the board.
- 2. Use at least two vias for V<sub>CC</sub> and ground connections of decoupling capacitors to minimize effective via-inductance.
- 3. Use 1-k $\Omega$  to 10-k $\Omega$  pull-up and pull-down resistors for enable lines to limit noise currents in theses lines during transient events.

#### 12.2 Layout Example

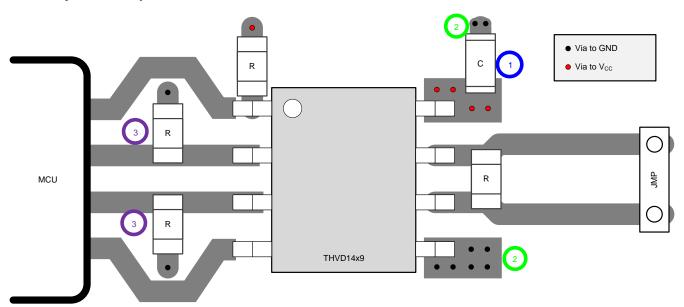


Figure 27. Half-Duplex Layout Example



### 13 Device and Documentation Support

#### 13.1 Device Support

#### 13.2 Third-Party Products Disclaimer

TI'S PUBLICATION OF INFORMATION REGARDING THIRD-PARTY PRODUCTS OR SERVICES DOES NOT CONSTITUTE AN ENDORSEMENT REGARDING THE SUITABILITY OF SUCH PRODUCTS OR SERVICES OR A WARRANTY, REPRESENTATION OR ENDORSEMENT OF SUCH PRODUCTS OR SERVICES, EITHER ALONE OR IN COMBINATION WITH ANY TI PRODUCT OR SERVICE.

#### 13.3 Related Links

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to order now.

**Table 3. Related Links** 

PARTS	PRODUCT FOLDER	ODUCT FOLDER ORDER NOW TECHNICAL DOCUMENTS		TOOLS & SOFTWARE	SUPPORT & COMMUNITY
THVD1419	Click here	Click here	Click here	Click here	Click here
THVD1429	Click here	Click here	Click here	Click here	Click here

#### 13.4 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document..

#### 13.5 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community T's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

**Design Support** *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

#### 13.6 Trademarks

E2E is a trademark of Texas Instruments.

#### 13.7 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

#### 13.8 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

### 14 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.







10-Dec-2020

#### **PACKAGING INFORMATION**

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
THVD1419DR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	1419	Samples
THVD1419DT	ACTIVE	SOIC	D	8	250	RoHS & Green	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	1419	Samples
THVD1429DR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	1429	Samples
THVD1429DT	ACTIVE	SOIC	D	8	250	RoHS & Green	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	1429	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and



## **PACKAGE OPTION ADDENDUM**

10-Dec-2020

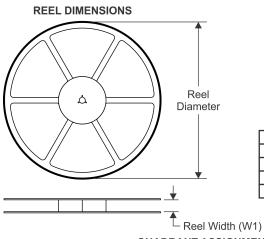
continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

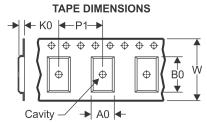
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

## PACKAGE MATERIALS INFORMATION

www.ti.com 18-Sep-2019

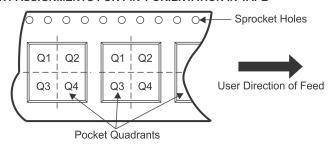
### TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

All differsions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
THVD1419DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
THVD1419DT	SOIC	D	8	250	177.8	12.4	6.4	5.2	2.1	8.0	12.0	Q1
THVD1429DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
THVD1429DT	SOIC	D	8	250	177.8	12.4	6.4	5.2	2.1	8.0	12.0	Q1

www.ti.com 18-Sep-2019



\*All dimensions are nominal

7 till dillitorioriorio di o mominar							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
THVD1419DR	SOIC	D	8	2500	346.0	346.0	29.0
THVD1419DT	SOIC	D	8	250	213.0	191.0	35.0
THVD1429DR	SOIC	D	8	2500	346.0	346.0	29.0
THVD1429DT	SOIC	D	8	250	213.0	191.0	35.0



SMALL OUTLINE INTEGRATED CIRCUIT



### NOTES:

- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



#### NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



#### IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, or other requirements. These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

Tl's products are provided subject to Tl's Terms of Sale (<a href="www.ti.com/legal/termsofsale.html">www.ti.com/legal/termsofsale.html</a>) or other applicable terms available either on ti.com or provided in conjunction with such Tl products. Tl's provision of these resources does not expand or otherwise alter Tl's applicable warranties or warranty disclaimers for Tl products.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2020, Texas Instruments Incorporated